

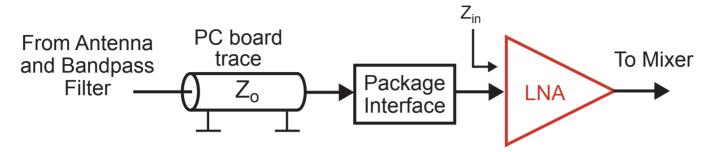
6.976 High Speed Communication Circuits and Systems Lecture 9 Low Noise Amplifiers

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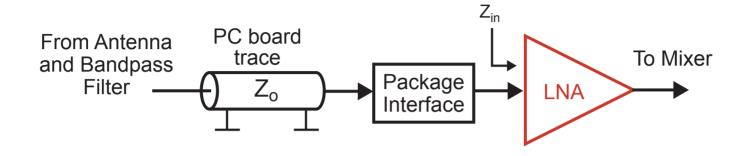
Narrowband LNA Design for Wireless Systems



Design Issues

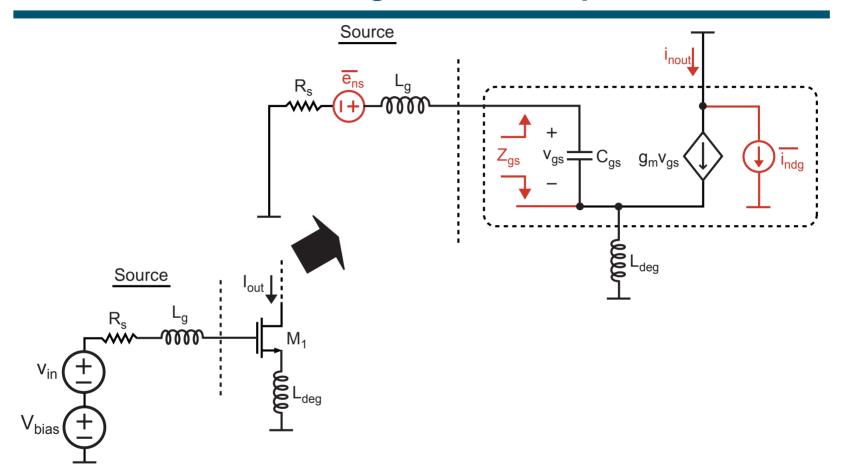
- Noise Figure impacts receiver sensitivity
- Linearity (IIP3) impacts receiver blocking performance
- Gain high gain reduces impact of noise from components that follow the LNA (such as the mixer)
- Power match want Z_{in} = Z_o (usually = 50 Ohms)
- Power want low power dissipation
- Bandwidth need to pass the entire RF band for the intended radio application (i.e., all of the relevant channels)
- Sensitivity to process/temp variations need to make it manufacturable in high volume

Our Focus in This Lecture



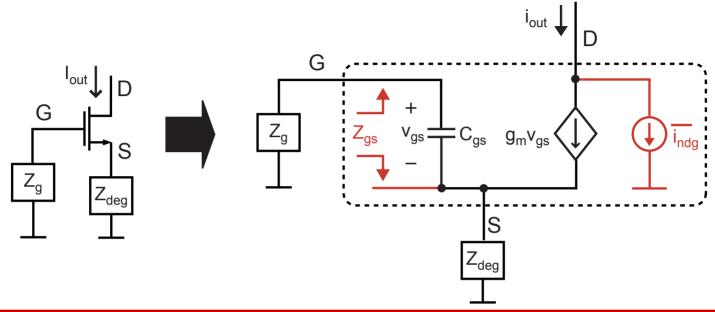
- Designing for low Noise Figure
- Achieving a good power match
- Hints at getting good IIP3
- Impact of power dissipation on design
- Tradeoff in gain versus bandwidth

Our Focus: Inductor Degenerated Amp



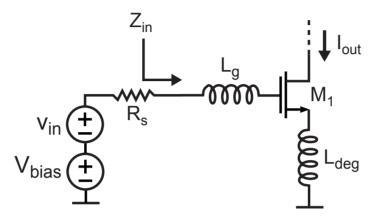
- Same as amp in Lecture 7 except for inductor degeneration
 - Note that noise analysis in Tom Lee's book does not include inductor degeneration (i.e., Table 11.1)

Recall Small Signal Model for Noise Calculations



$$\begin{split} & \frac{\overline{i_{ndg}^2}}{\Delta f} = \frac{\overline{i_{nd}^2}}{\Delta f} \left(|\eta|^2 + 2Re \left\{ c \chi_d \eta^* Z_{gsw} \right\} + \chi_d^2 |Z_{gsw}|^2 \right) \\ & \text{where: } & \frac{\overline{i_{nd}^2}}{\Delta f} = 4kT \gamma g_{do}, \; \chi_d = \frac{g_m}{g_{do}} \sqrt{\frac{\delta}{5\gamma}}, \; Z_{gsw} = w C_{gs} Z_{gs} \\ & Z_{gs} = \frac{1}{s C_{gs}} \Big| \Big| \frac{Z_{deg} + Z_g}{1 + g_m Z_{deg}} \qquad \eta = 1 - \left(\frac{g_m Z_{deg}}{Z_{deg} + Z_g} \right) Z_{gs} \end{split}$$

Key Assumption: Design for Power Match



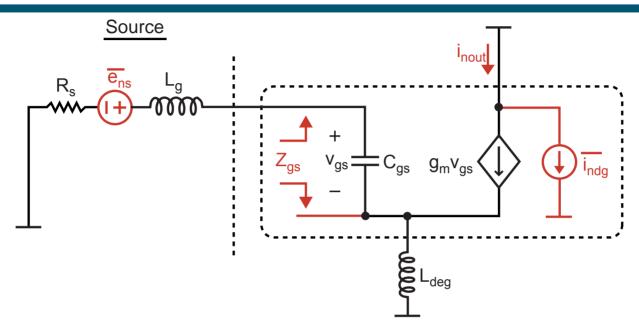
Input impedance (from Lec 6)

$$Z_{in}(s) = \frac{1}{sC_{gs}} + s(L_{deg} + L_g) + \frac{g_m}{C_{gs}}L_{deg}$$
Real!

Set to achieve pure resistance = R_s at frequency w_o

$$\Rightarrow \frac{1}{\sqrt{(L_g + L_{deg})C_{gs}}} = w_o, \quad \frac{g_m}{C_{gs}}L_{deg} = R_s$$

Process and Topology Parameters for Noise Calculation



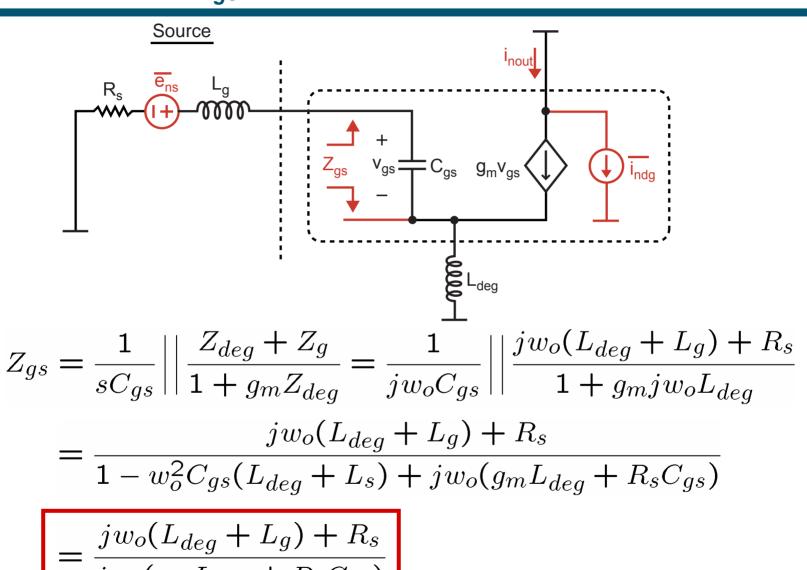
- Process parameters
 - For 0.18μ CMOS, we will assume the following

$$c = -j0.55$$
, $\gamma = 3$, $\delta = 2\gamma = 6$, $\frac{g_m}{g_{do}} = \frac{1}{2} \Rightarrow \chi_d = 0.32$

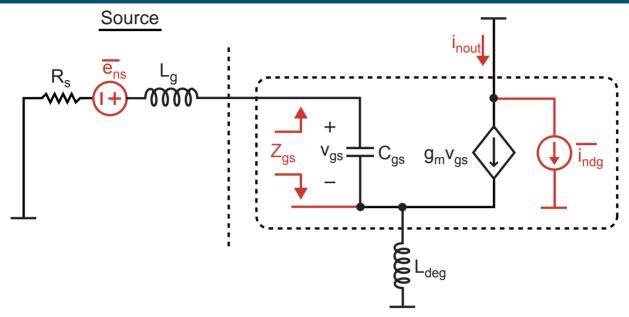
Circuit topology parameters Z_g and Z_{deg}

$$Z_g = R_s + jwL_g, \quad Z_{deg} = jwL_{deg}$$

Calculation of Z_{as}



Calculation of η



$$\eta = 1 - \left(\frac{g_m Z_{deg}}{Z_{deg} + Z_g}\right) Z_{gs} = 1 - \frac{g_m j w_o L_{deg}}{j w_o (L_{deg} + L_g) + R_s} Z_{gs}
= 1 - \frac{g_m j w_o L_{deg}}{j w_o (g_m L_{deg} + R_s C_{gs})} = 1 - \frac{(g_m / C_{gs}) L_{deg}}{(g_m / C_{gs}) L_{deg} + R_s}
= 1 - \frac{R_s}{I_{gs}} = I_{gs}$$

Calculation of Z_{qsw}

By definition

$$Z_{gsw} = w_o C_{gs} Z_{gs} \quad \left(Q = \frac{1}{w_o C_{gs} 2R_s} = \frac{w_o (L_g + L_{deg})}{2R_s} \right)$$

Calculation

$$Z_{gsw} = w_o C_{gs} \frac{j w_o (L_{deg} + L_g) + R_s}{j w_o (g_m L_{deg} + R_s C_{gs})}$$

$$= \frac{j w_o^2 C_{gs} (L_{deg} + L_g) + w_o C_{gs} R_s}{j w_o (g_m L_{deg} + R_s C_{gs})}$$

$$= \frac{j 1 + 1/(2Q)}{j w_o (g_m L_{deg} + R_s C_{gs})}$$

$$= \frac{j 1 + 1/(2Q)}{j w_o C_{gs} ((g_m / C_{gs}) L_{deg} + R_s)}$$

$$= \frac{j 1 + 1/(2Q)}{j w_o C_{gs} ((g_m / C_{gs}) L_{deg} + R_s)}$$

$$= \frac{j1 + 1/(2Q)}{jw_o C_{gs}(R_s + R_s)} = \frac{j1 + 1/(2Q)}{j1/Q} = \begin{bmatrix} \frac{1}{2}(2Q - j) \end{bmatrix}$$

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Calculation of Output Current Noise

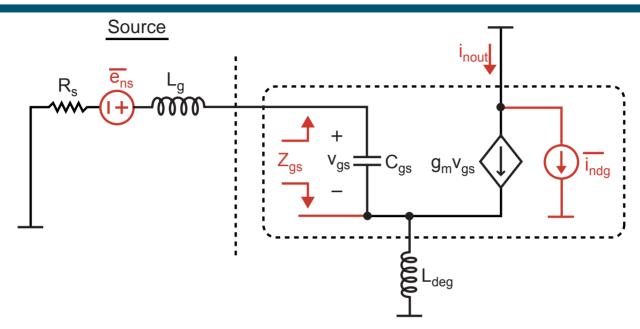
Step 3: Plug in values to noise expression for indg

$$\frac{\overline{i_{ndg}^2}}{\Delta f} = \frac{\overline{i_{nd}^2}}{\Delta f} \left(|\eta|^2 + 2Re \left\{ -j|c|\chi_d \eta^* Z_{gsw} \right\} + \chi_d^2 |Z_{gsw}|^2 \right)$$
where $\eta = \frac{1}{2}$, $Z_{gsw} = \frac{1}{2} (2Q - j)$

$$\Rightarrow \frac{\overline{i_{ndg}^2}}{\Delta f} = \frac{\overline{i_{nd}^2}}{\Delta f} \left(\frac{1}{4} + 2Re \left\{ -j|c|\chi_d \frac{1}{4} (2Q - j) \right\} + \chi_d^2 \frac{1}{4} |2Q - j|^2 \right)$$

$$= \frac{\overline{i_{nd}^2}}{\Delta f} \frac{1}{4} \left(1 - 2|c|\chi_d + \chi_d^2 (4Q^2 + 1) \right)$$

Compare Noise With and Without Inductor Degeneration



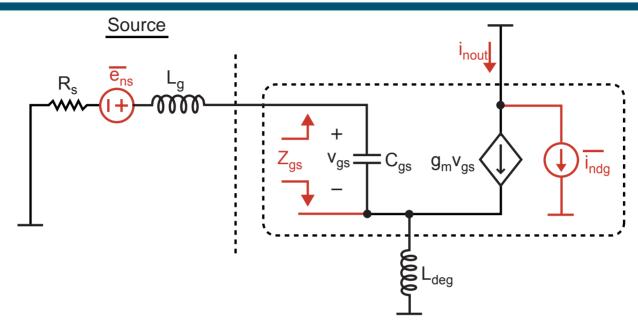
From Lecture 7, we derived for $L_{deg} = 0$, $w_o^2 = 1/(L_g C_{gs})$

$$\frac{\overline{i_{ndg}^2}}{\Delta f} = \frac{\overline{i_{nd}^2}}{\Delta f} \left(1 - 2|c|\chi_d + \chi_d^2(Q^2 + 1) \right)$$

• We now have for $(g_m/C_{gs})L_{deg} = R_s$, $w_o^2 = 1/((L_g + L_{deg})C_{gs})$

$$\frac{\overline{i_{ndg}^2}}{\Delta f} = \frac{\overline{i_{nd}^2}}{\Delta f} \frac{1}{4} \left(1 - 2|c|\chi_d + \chi_d^2 (4Q^2 + 1) \right)$$

Derive Noise Factor for Inductor Degenerated Amp

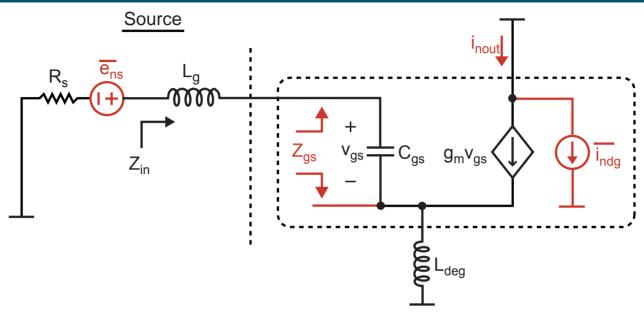


Recall the alternate expression for Noise Factor derived in Lecture 8

$$F = \frac{\text{total output noise power}}{\text{output noise due to input source}} = \frac{i_{nout(tot)}^2}{\overline{i_{nout(in)}^2}}$$

- We now know the output noise due to the transistor noise
 - We need to determine the output noise due to the source resistance

Output Noise Due to Source Resistance



$$Z_{in} = \frac{1}{jw_o C_{gs}} + jw_o (L_{deg} + L_g) + \frac{g_m}{C_{gs}} L_{deg} = R_s$$

$$\Rightarrow v_{gs} = \frac{\overline{e_{ns}}}{R_s + Z_{in}} \left(\frac{1}{jw_o C_{gs}} \right) = \frac{\overline{e_{ns}}}{2R_s} \left(\frac{1}{jw_o C_{gs}} \right) = \left(\frac{Q}{j} \right) \overline{e_{ns}}$$

$$\Rightarrow i_{nout} = g_m \left(\frac{Q}{j}\right) \overline{e_{ns}}$$

$$\Rightarrow \overline{i_{nout}^2} = (g_m Q)^2 \overline{e_{ns}^2}$$

Noise Factor for Inductor Degenerated Amplifier

Noise Factor
$$= \frac{(g_m Q)^2 \overline{e_{ns}^2} + \overline{i_{ndg}^2}/\Delta f}{(g_m Q)^2 \overline{e_{ns}^2}} = 1 + \frac{\overline{i_{ndg}^2}/\Delta f}{(g_m Q)^2 \overline{e_{ns}^2}}$$

$$= 1 + \frac{4kT\gamma g_{do}(1/4)(1 - 2|c|\chi_d + \chi_d^2(4Q^2 + 1))}{(g_m Q)^2 4kTR_s}$$

$$= 1 + \left(\frac{1}{g_m QR_s}\right) \gamma \left(\frac{g_{do}}{g_m}\right) \frac{1}{4Q} \left(1 - 2|c|\chi_d + (4Q^2 + 1)\chi_d^2\right)$$

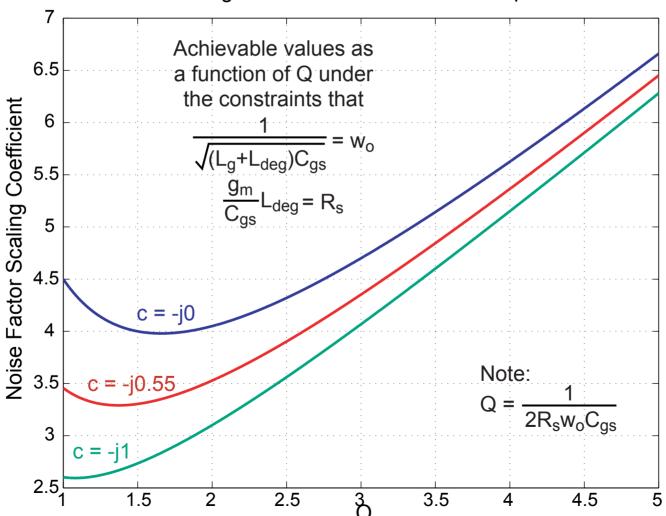
$$= 1 + \left(\frac{2w_o R_s C_{gs}}{g_m R_s}\right) \gamma \left(\frac{g_{do}}{g_m}\right) \frac{1}{4Q} \left(1 - 2|c|\chi_d + (4Q^2 + 1)\chi_d^2\right)$$

$$= 1 + \left(\frac{w_o}{w_t}\right) \gamma \left(\frac{g_{do}}{g_m}\right) \frac{1}{2Q} \left(1 - 2|c|\chi_d + (4Q^2 + 1)\chi_d^2\right)$$

Noise Factor scaling coefficient

Noise Factor Scaling Coefficient Versus Q

Noise Factor Scaling Coefficient Versus Q for 0.18 μ NMOS Device



Achievable Noise Figure in 0.18 µ with Power Match

- Suppose we desire to build a narrowband LNA with center frequency of 1.8 GHz in 0.18µ CMOS (c=-j0.55)
 - From Hspice at V_{gs} = 1 V with NMOS (W=1.8 μ , L=0.18 μ)
 - measured g_m =871 μ S, C_{qs} = 2.9 fF

$$\Rightarrow w_t \approx \frac{g_m}{C_{gs}} = \frac{871 \times 10^{-6}}{2.9 \times 10^{-15}} = 2\pi (47.8GHz)$$

$$\Rightarrow \frac{w_o}{w_t} = \frac{2\pi 1.8e9}{2\pi 47.8e9} \approx \frac{1}{26.6}$$

- Looking at previous curve, with Q \approx 2 we achieve a Noise Factor scaling coefficient \approx 3.5
 - \Rightarrow Noise Factor $\approx 1 + \frac{1}{26.6} 3.5 \approx 1.13$
 - \Rightarrow Noise Figure = $10 \log(1.13) \approx 0.53 dB$

Component Values for Minimum NF with Power Match

- Assume $R_s = 50$ Ohms, Q = 2, $f_o = 1.8$ GHz, $f_t = 47.8$ GHz
 - C_{qs} calculated as

$$Q = \frac{1}{2R_s w_o C_{gs}}$$

$$\Rightarrow C_{gs} = \frac{1}{2R_s w_o Q} = \frac{1}{2(50)2\pi 1.8e9(2)} = \boxed{442fF}$$

L_{deg} calculated as

$$\frac{g_m}{C_{gs}}L_{deg} = R_s \implies L_{deg} = \frac{R_s}{w_t} = \frac{50}{2\pi 47.8e9} = 0.17nH$$

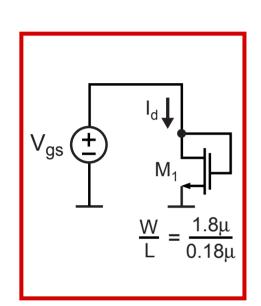
L_a calculated as

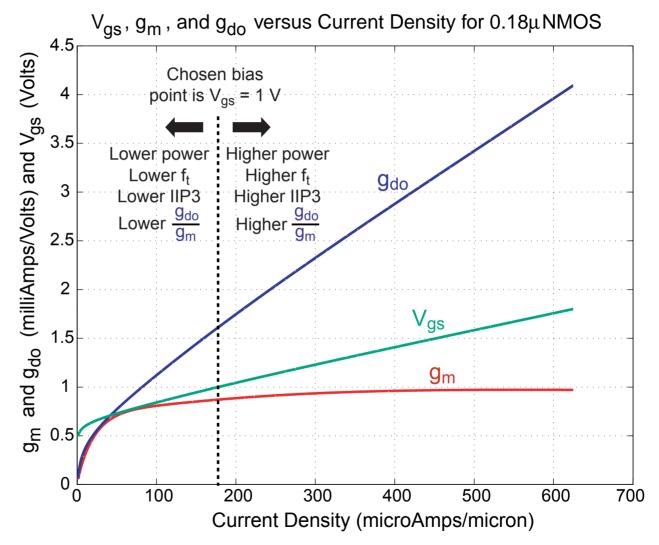
$$\frac{1}{\sqrt{(L_g + L_{deg})C_{gs}}} = w_o \Rightarrow L_g = \frac{1}{w_o^2 C_{gs}} - L_{deg}$$

$$\Rightarrow L_g = \frac{1}{(2\pi 1.8e9)^2 442e - 15} - 0.17e - 9 = \boxed{17.5nH}$$

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Have We Chosen the Correct Bias Point? $(V_{qs} = 1V)$





Note: IIP3 is also a function of Q

Calculation of Bias Current for Example Design

Calculate current density from previous plot

$$V_{gs} = 1V \Rightarrow I_{dens} \approx 175 \mu A / \mu m$$

Calculate W from Hspice simulation (assume L=0.18 μm)

$$C_{gs} = 2.9 fF \text{ for } W = 1.8 \mu m \implies W = \frac{442 fF}{2.9 fF} 1.8 \mu m \approx 274 \mu m$$

- Could also compute this based on C_{ox} value
- Calculate bias current

$$I_{bias} = I_{den}W = (175\mu A/\mu m)(274\mu m) \approx 48mA$$

Problem: this is not low power!!

We Have Two "Handles" to Lower Power Dissipation

Key formulas

$$I_{bias} = I_{den}W$$

$$F = 1 + \left(\frac{w_o}{w_t}\right) \gamma \left(\frac{g_{do}}{g_m}\right) \frac{1}{2Q} \left(1 - 2|c|\chi_d + (4Q^2 + 1)\chi_d^2\right)$$

- Lower current density, I_{den}
 - Benefits

$$\Rightarrow$$
 lower power, lower $\frac{g_{do}}{g_m}$ ratio

Negatives

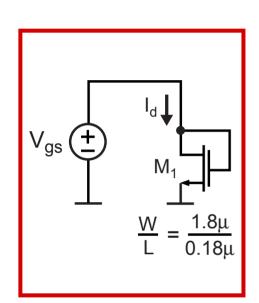
$$\Rightarrow$$
 lower IIP3, lower f_t

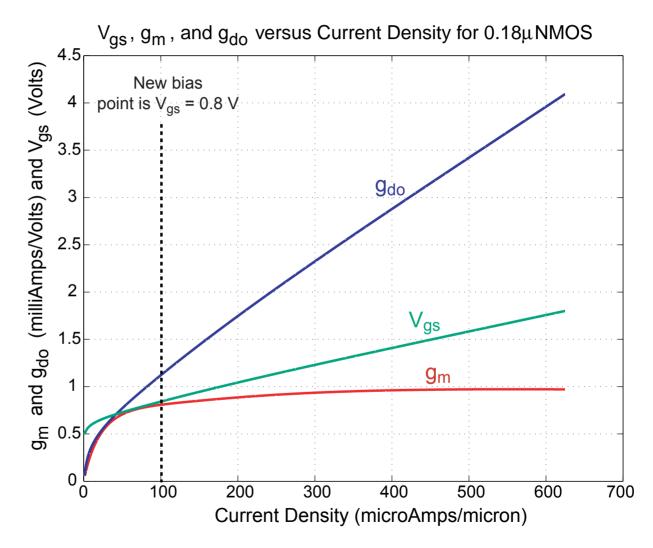
- Lower W
 - Benefit: lower power
 - Negatives

$$\Rightarrow$$
 lower $C_{gs} = \frac{2}{3}WLC_{ox} \Rightarrow$ higher $Q = \frac{1}{w_oC_{gs}2R_s}$

 \Rightarrow higher F (and higher inductor values)

First Step in Redesign - Lower Current Density, I_{den}





Need to verify that IIP3 still OK (once we know Q)

Recalculate Process Parameters

- Assume that the only thing that changes is g_m/g_{do} and f_t
 - From previous graph (I_{den} = 100 μ A/ μ m)

$$\frac{g_m}{g_{do}} \approx \frac{.78}{1.15} \approx 0.68 \Rightarrow \chi_d = \frac{g_m}{g_{do}} \sqrt{\frac{\delta}{5\gamma}} = 0.63 \sqrt{\frac{2}{5}} \approx 0.43$$

$$w_t \approx \frac{g_m}{2\pi} \approx 0.78 \text{m/s} = (2\pi)42.8 \text{CHz}$$

$$w_t \approx \frac{g_m}{C_{gs}} \approx \frac{0.78mS}{2.9fF} = (2\pi)42.8GHz$$

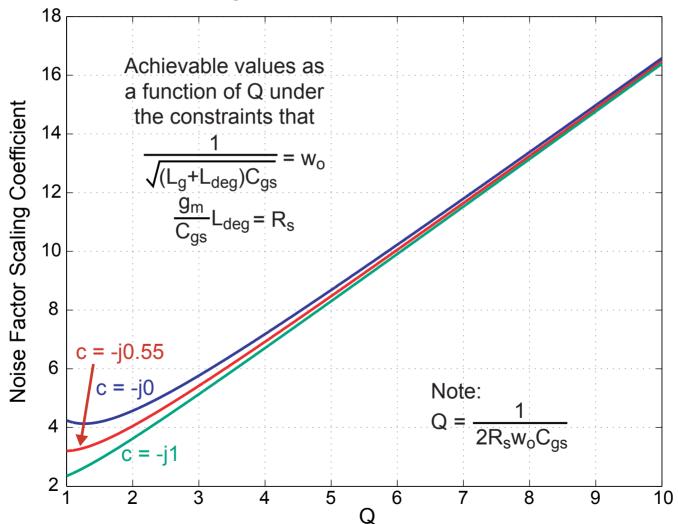
- We now need to replot the Noise Factor scaling coefficient
 - Also plot over a wider range of Q

$$F = 1 + \left(\frac{w_o}{w_t}\right) \gamma \left(\frac{g_{do}}{g_m}\right) \frac{1}{2Q} \left(1 - 2|c|\chi_d + (4Q^2 + 1)\chi_d^2\right)$$

Noise Factor scaling coefficient

Update Plot of Noise Factor Scaling Coefficient

Noise Factor Scaling Coefficient Versus Q for 0.18 µ NMOS Device



Second Step in Redesign - Lower W

Recall $C_{gs} = \frac{2}{3}WLC_{ox}, \quad Q = \frac{1}{w_oC_{as}2R_s}$

I_{bias} can be related to Q as

$$I_{bias} = I_{den}W = I_{den}\frac{3}{2LC_{ox}}C_{gs} = I_{den}\frac{3}{2LC_{ox}}\frac{1}{w_o 2R_s Q}$$

$$\Rightarrow I_{bias} \propto \frac{1}{Q}$$

- We previously chose Q = 2, let's now choose Q = 6
 - Cuts power dissipation by a factor of 3!
 - New value of W is one third the old one

$$\Rightarrow W = \frac{274fF}{3} \approx \boxed{91\mu m}$$

Power Dissipation and Noise Figure of New Design

Power dissipation

$$I_{bias} = I_{den}W = (100\mu A/\mu m)(91\mu m) = 9.1mA$$

At 1.8 V supply

$$\Rightarrow$$
 Power = $(9.1mA)(1.8V) = 16.4mW$

Noise Figure

¬ f₁ previously calculated, get scaling coeff. from plot

$$\frac{w_o}{w_t} = \frac{2\pi 1.8e9}{2\pi 42.8e9} \approx \frac{1}{23.8}$$
, scaling coeff. ≈ 10

$$\Rightarrow$$
 Noise Factor $\approx 1 + \frac{1}{23.8} 10 \approx 1.42$

$$\Rightarrow$$
 Noise Figure = $10 \log(1.42) \approx 1.52 \, dB$

Updated Component Values

- **Assume** $R_s = 50$ Ohms, Q = 6, $f_o = 1.8$ GHz, $f_t = 42.8$ GHz
 - C_{as} calculated as

$$Q = \frac{1}{2R_s w_o C_{gs}}$$

$$\Rightarrow C_{gs} = \frac{1}{2R_s w_o Q} = \frac{1}{2(50)2\pi 1.8e9(6)} \approx \boxed{147fF}$$

L_{deg} calculated as

$$\frac{g_m}{C_{gs}}L_{deg} = R_s \implies L_{deg} = \frac{R_s}{w_t} = \frac{50}{2\pi 42.8e9} = \boxed{0.19nH}$$

L_a calculated as

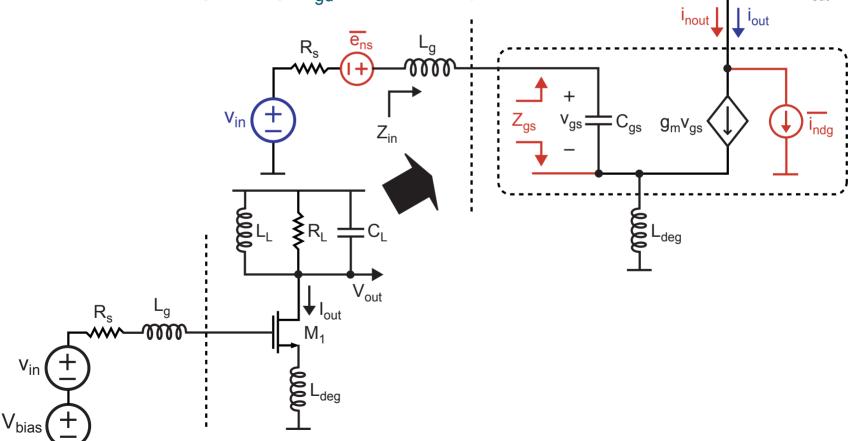
$$\frac{1}{\sqrt{(L_g + L_{deg})C_{gs}}} = w_o \Rightarrow L_g = \frac{1}{w_o^2 C_{gs}} - L_{deg}$$

$$\Rightarrow L_g = \frac{1}{(2\pi 1.8e^9)^2 147e - 15} - 0.19e - 9 = \boxed{53nH}$$

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Inclusion of Load (Resonant Tank)

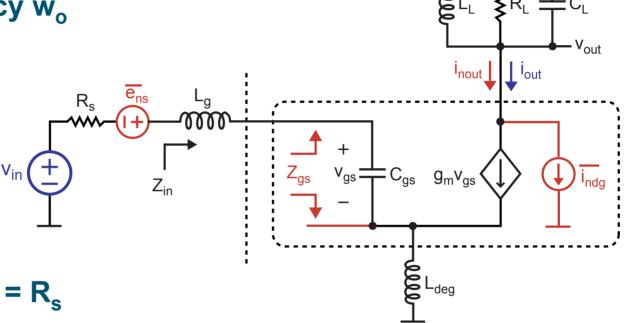
- Add output load to achieve voltage gain
 - Note: in practice, use cascode device
 - We're ignoring C_{qd} in this analysis



 R_L

Calculation of Gain

 Assume load tank resonates at frequency w_o



Assume Z_{in} = R_s

$$\Rightarrow v_{gs} = \frac{v_{in}}{2R_s} \left(\frac{1}{jw_o C_{gs}} \right) = \left(\frac{Q}{j} \right) v_{in}$$

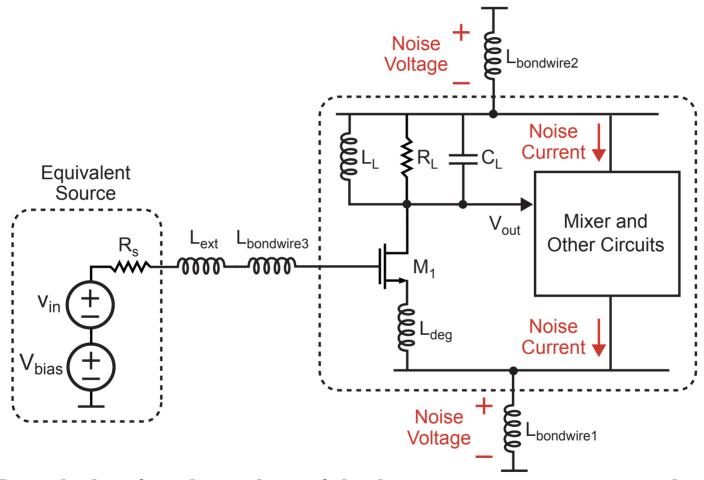
$$\Rightarrow i_{out} = g_m \left(\frac{Q}{j}\right) v_{in} \qquad \Rightarrow v_{out} = -g_m R_L \left(\frac{Q}{j}\right) v_{in}$$

Setting of Gain

$$|\mathsf{Gain}| = g_m R_L Q$$

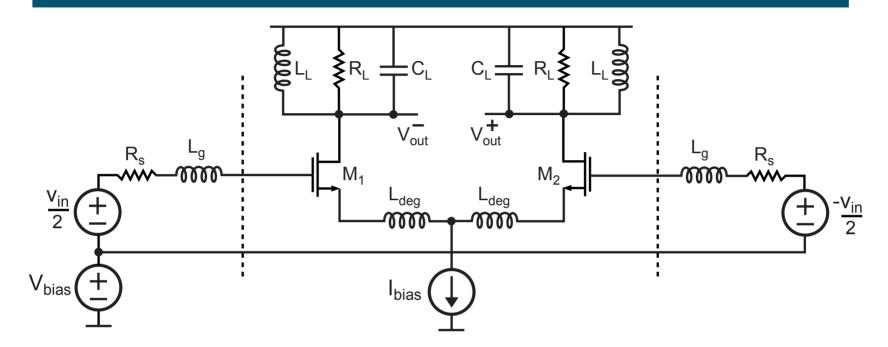
- Parameters g_m and Q were set by Noise Figure and IIP3 considerations
 - Note that Q is of the input matching network, not the amplifier load
- R_L is the free parameter use it to set the desired gain
 - Note that higher R_L for a given resonant frequency and capacitive load will increase Q_L (i.e., Q of the amplifier load)
 - There is a tradeoff between amplifier bandwidth and gain
 - Generally set R_L according to overall receiver noise and IIP3 requirements (higher gain is better for noise)
 - Very large gain (i.e., high Q_L) is generally avoided to minimize sensitivity to process/temp variations that will shift the center frequency

The Issue of Package Parasitics



- Bondwire (and package) inductance causes two issues
 - Value of degeneration inductor is altered
 - Noise from other circuits couples into LNA

Differential LNA



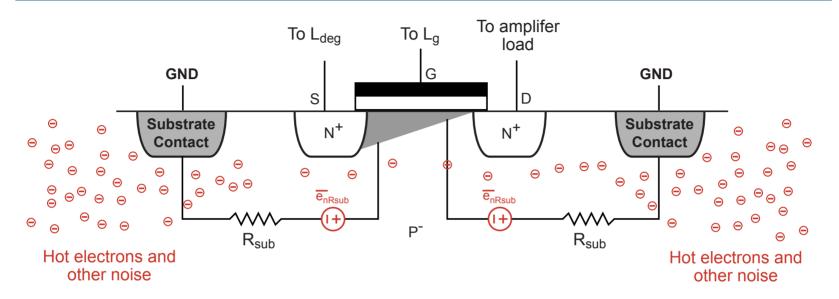
Advantages

- Value of L_{deg} is now much better controlled
- Much less sensitivity to noise from other circuits

Disadvantages

- Twice the power as the single-ended version
- Requires differential input at the chip

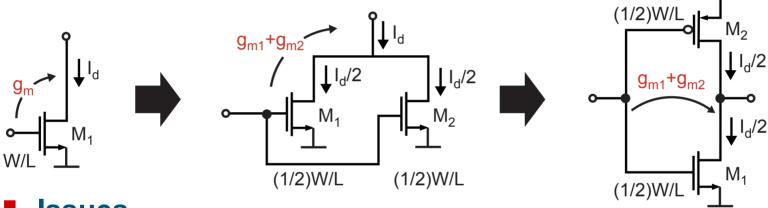
Note: Be Generous with Substrate Contact Placement



- Having an abundance of nearby substrate contacts helps in three ways
 - Reduces possibility of latch up issues
 - Lowers R_{sub} and its associated noise
 - Impacts LNA through backgate effect (g_{mb})
 - Absorbs stray electrons from other circuits that will otherwise inject noise into the LNA
- Negative: takes up a bit extra area

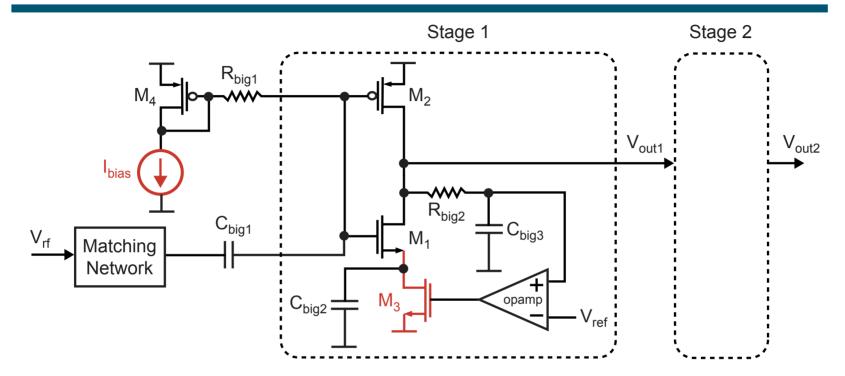
Another CMOS LNA Topology

- Consider increasing g_m for a given current by using both PMOS and NMOS devices
 - Key idea: re-use of current



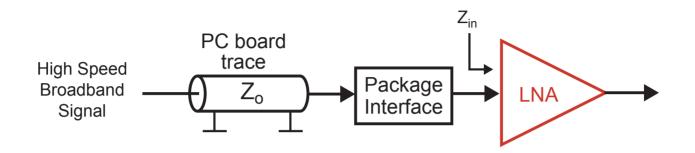
- Issues
 - PMOS device has poorer transconductance than NMOS for a given amount of current, and f_t is lower
 - Not completely clear there is an advantage to using this technique, but published results are good
 - See A. Karanicolas, "A 2.7 V 900-MHz CMOS LNA and Mixer", JSSC, Dec 1996

Biasing for LNA Employing Current Re-Use



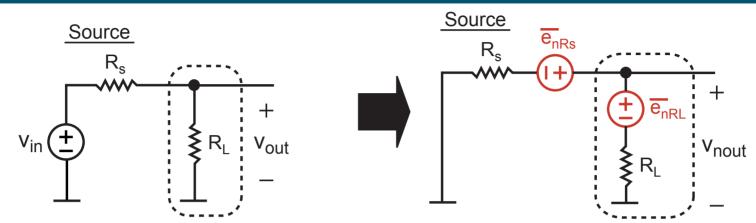
- PMOS is biased using a current mirror
- NMOS current adjusted to match the PMOS current
- Note: not clear how the matching network is achieving a 50 Ohm match
 - Perhaps parasitic bondwire inductance is degenerating the PMOS or NMOS transistors?

Broadband LNA Design



- Most broadband systems are not as stringent on their noise requirements as wireless counterparts
- Equivalent input voltage is often specified rather than a Noise Figure
- Typically use a resistor to achieve a broadband match to input source
 - We know from Lecture 8 that this will limit the noise figure to be higher than 3 dB
- For those cases where low Noise Figure is important, are there alternative ways to achieve a broadband match?

Recall Noise Factor Calculation for Resistor Load



Total output noise

$$\overline{v_{nout(tot)}^2} = \left(\frac{R_L}{R_s + R_L}\right)^2 \overline{e_{nRs}^2} + \left(\frac{R_s}{R_s + R_L}\right)^2 \overline{e_{nRL}^2}$$

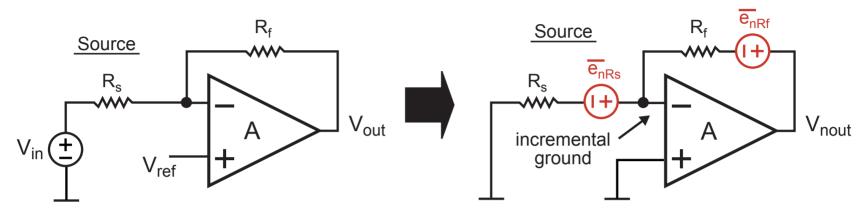
Total output noise due to source

$$\overline{v_{nout(in)}^2} = \left(\frac{R_L}{R_s + R_L}\right)^2 \overline{e_{nRs}^2}$$

Noise Factor

$$F = 1 + \left(\frac{R_s}{R_L}\right)^2 \frac{\overline{e_{nRL}^2}}{\overline{e_{nRs}^2}} = 1 + \left(\frac{R_s}{R_L}\right)^2 \frac{4kTR_L}{4kTR_s} = 1 + \frac{R_s}{R_L}$$

Noise Figure For Amp with Resistor in Feedback



Total output noise (assume A is large)

$$\overline{v_{nout(tot)}^2} \approx \left(\frac{-R_f}{R_s}\right)^2 \overline{e_{nRs}^2} + \overline{e_{nRf}^2}$$

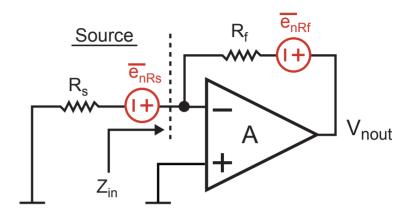
Total output noise due to source (assume A is large)

$$\overline{v_{nout(in)}^2} \approx \left(\frac{-R_f}{R_s}\right)^2 \overline{e_{nRs}^2}$$

Noise Factor

$$F \approx 1 + \left(\frac{R_s}{R_f}\right)^2 \frac{e_{nRf}^2}{e_{nRs}^2} = 1 + \left(\frac{R_s}{R_f}\right)^2 \frac{4kTR_f}{4kTR_s} = 1 + \frac{R_s}{R_f}$$

Input Impedance For Amp with Resistor in Feedback



Recall from Miller effect discussion that

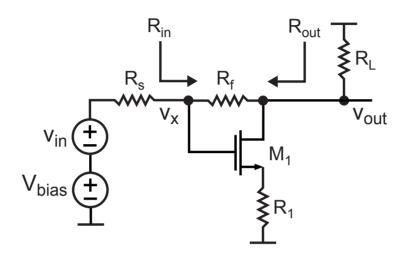
$$Z_{in} = \frac{Z_f}{1 - qain} = \frac{R_f}{1 + A}$$

■ If we choose Z_{in} to match R_s, then

$$R_f = (1+A)Z_{in} = (1+A)R_s$$

Therefore, Noise Figure lowered by being able to choose a large value for $R_{\rm f}$ since $F \approx 1 + \frac{R_s}{R_s}$

Example - Series-Shunt Amplifier



- Recall that the above amplifier was analyzed in Lecture 5
- Tom Lee points out that this amplifier topology is actually used in noise figure measurement systems such as the Hewlett-Packard 8970A
 - It is likely to be a much higher performance transistor than a CMOS device, though